

SENSORS PRODUCT LINE TEST PROCEDURES

TYPICAL TEST PROCEDURES USED BY MICRO-MEASUREMENTS FOR APPROPRIATE SENSOR PRODUCTS	
Optical Defect Analysis :	Micro-Measurements Procedures and Standards
Gage Resistance at 24°C and 50%RH :	Micro-Measurements Procedures, National Institute of Standards and Technology Traceable Resistance Standards
Gage Factor at 24°C and 50%RH :	ASTM International E 251
Temperature Coefficient of Gage Factor :	ASTM International E 251
Thermal Output :	ASTM International E 251
Transverse Sensitivity at 24°C and 50%RH :	ASTM International E 251
Fatigue Life :	ASTM International E 1948
Strain Limits :	National Aerospace Standard-942 Modified
Gage Thickness :	Micro-Measurements Procedures
Creep and Drift :	Micro-Measurements Procedures, similar to NAS 942